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## (54) Optical disk device and replacement processing method

(57) In this invention, in an optical disk (1) on which data is to be recorded in units of one ECC block constructed by 16 sectors, dummy data is recorded at the manufacturing time or at the initial time such as the application starting time, then the dummy data is reproduced to determine a sector with primary defect, the address of the sector which is determined to have the primary defect is recorded on the optical disk (1), and at the time of data recording, data recording is effected in units of one ECC block while skipping over the sector with the primary defect. The determining condition for the primary defect is a case where address data of the address field cannot be reproduced, or where the number of rows in which the number of error bytes is four or more is five or more. Further, in the optical disk (1) on which data is to be recorded in units of one ECC block, data is recorded at the time of data recording other than the initial time, then the data is reproduced to determine an ECC block having a sector with secondary defect, and data of the ECC block which is determined to have the sector with secondary defect is recorded in an ECC block which is separately prepared. The determining condition for the secondary defect is a case where address data of the address field cannot be reproduced (first condition), where the number of rows in which the number of error bytes is four or more is five or more (second condition), where the number of rows in which the number of error bytes is four or more is not larger than five, the number of rows in which the number of error bytes is four or more is three or more and the number of rows in which the number of error bytes in one block area is four or more is ten or more, or where at least two sector areas in which the number of rows in which the number of error bytes is four or more is five or less and the number of rows in which the number of error bytes is four or more is three or more are present in one block area.

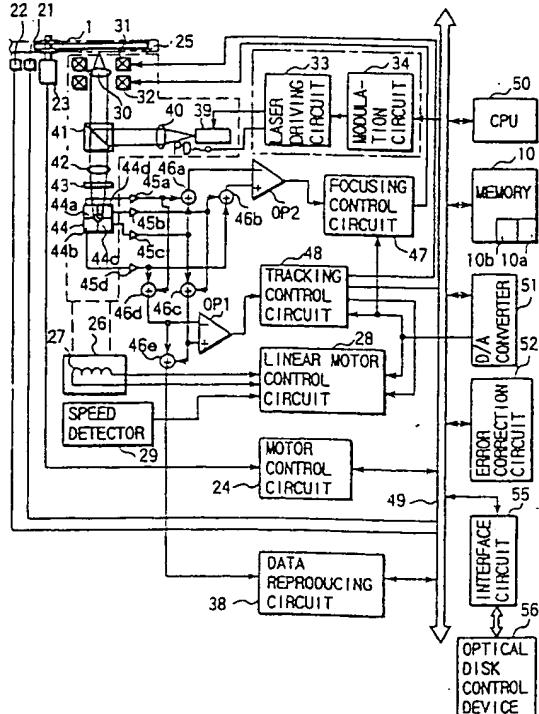


FIG. 1